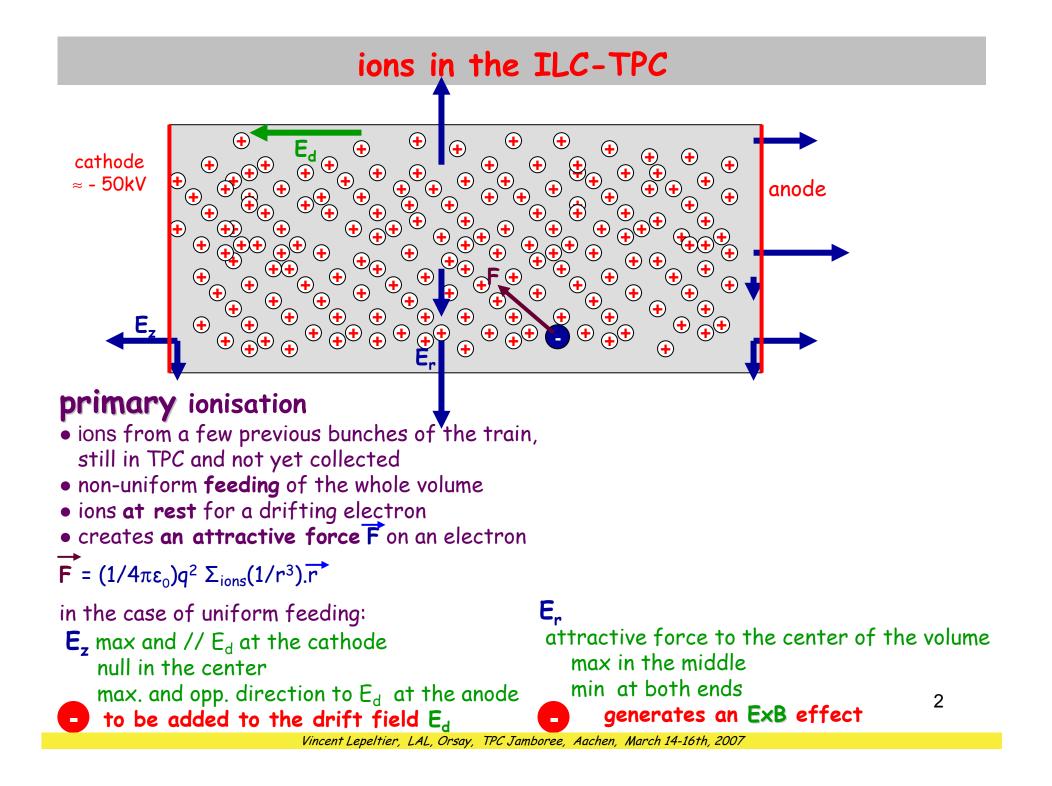
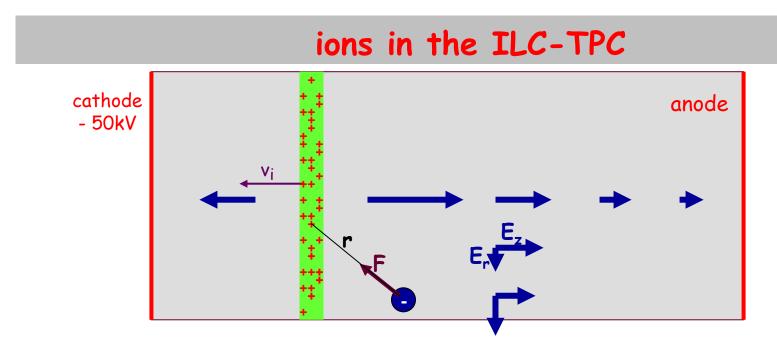


Vincent Lepeltier LAL, Orsay, France

outline

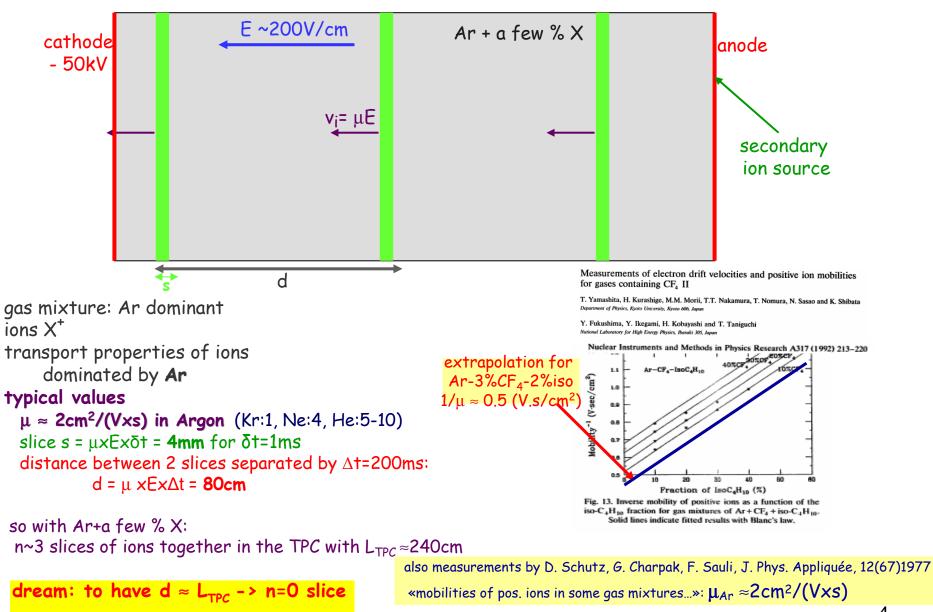
- introduction: what is the problem with the ions in the TPC?
- how to suppress secondary ions?
- how to translate occupancy into ion density?
- conclusion





secondary ionisation

- produced by the avalanches induced by (a few) previous train(s) and not yet collected by the cathode plane
- total secondary population: N_s=N_i×G×β (N_i= primary ionisation, G=gain, β=ion feedback) for a MPGD: G=1000-5000, β=2-10×10⁻³ -> N_s≈2-10×N_i but ρ_s≈(Ns/Ni)×200×ρ_i ≈10³× ρ_i
- small slice of ions, at rest for an electron $(v_i \ll v_e)$
 - slice size s= V_i . δt (δt =1ms) $\approx \underline{a} f e w$ mm.
- creates an attractive force \vec{F} on a drifting electron $\vec{F} = (1/4\pi\epsilon_0)q^2 \Sigma(1/r^3).\vec{r}$
- in the case of uniform feeding of the ion slice:
- E_z is added (sudtracted) to the drift field E_d
- $\mathbf{E}_{\mathbf{r}}$ creates a radial drift + $\mathbf{E} \times \mathbf{B}$ effects
 - distortions of the trajectory HOW MUCH???
 - simulation and/or analytic calculation needed



how to suppress the secondary ionisation?

-> collect ions before the next train (200ms)

1. collect secondary ions on the cathode

to have 0 slice of ions in the TPC after 200ms

-> time collection: T=L_{TPC}/ μE = 240/2×200 \approx 600 ms and we want 200ms !!!

• decrease LTPC to 80cm NO!

• increase μ by a factor 3

for Ar, $\mu \approx 2$ cm2/(V.s), for lighter gases the mobility is higher for Ne $\mu \approx 3-4$,

for He μ_{He+} =10, but we have measured less than 5 at Saclay in 2002 Blanc's law for additivity of $1/\mu$: $1/\mu = \Sigma(\epsilon_i/\mu_i)$

we can imagine to add to Ar (a lot of) Ne or He

BUT v_e is smaller for mixtures with these gases, and max at higher E_d so three disadvantages at the same time:

- less ionisation,
- wt smaller ex. 5%CF4@4T wt=14 (Ar), 7(Ne), 1(He)
- larger HV on the cathode
- increase E or μ E by a factor 3

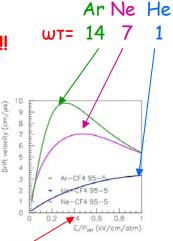
ex. use a mixing with Ar+He+ 5-6%CF4+iso-C4H10 with 400V/cm -> same problem with HV

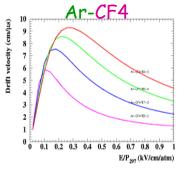
I think that the maximum we can get is a factor 1.5 to 2, not 3

→ conclusion: the TPC is at least 1.5 times too long for the 200ms time between trains

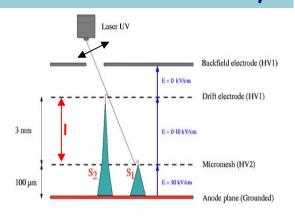
do we need to measure ion mobilities?

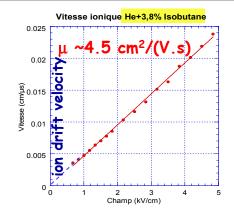
probably YES if we want to put a gating device.





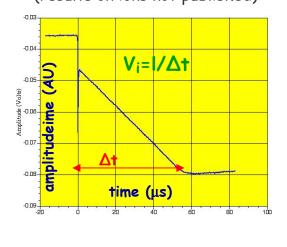
how to measure ion mobility?

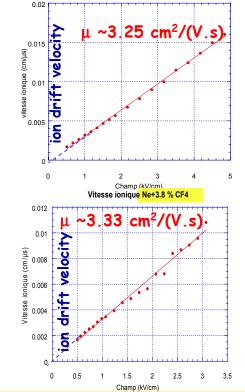




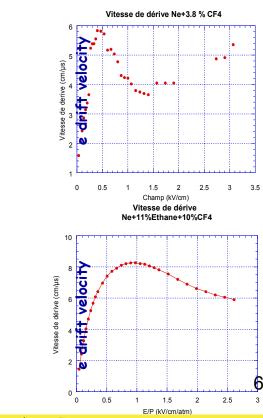
Vitesse ionique He+10 % Isobutane

very simple device already used at Saclay for e drift velocity measurement P. Colas, et al., NIMA478(215)2002. (results on ions not published)

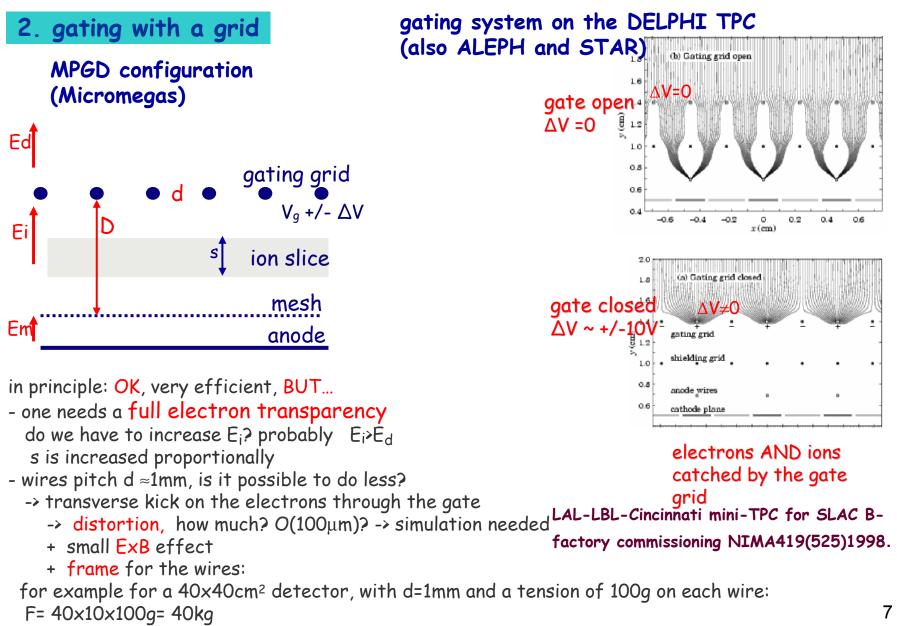




Vitesse de dérive He+3.8% Isobutane

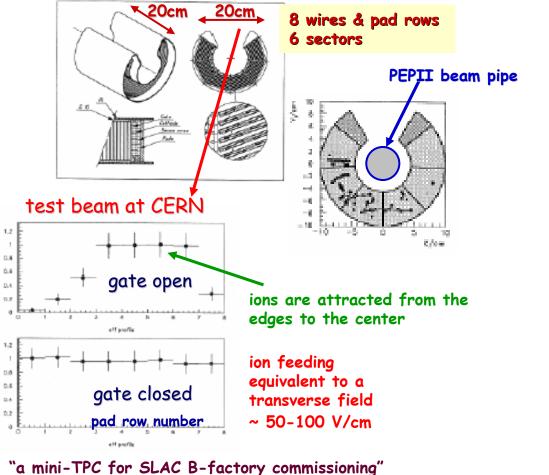


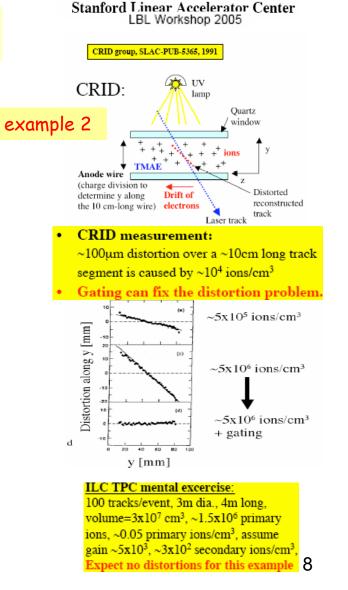
Vincent Lepeltier, LAL, Orsay, TPC Jamboree, Aachen, March 14-16th, 2007



field distortion examples:

example 1: LAL(VL)-LBL(Mike Ronan)-Cincinnati mini-TPC for PEP-II commissioning at SLAC (1997) before Babar

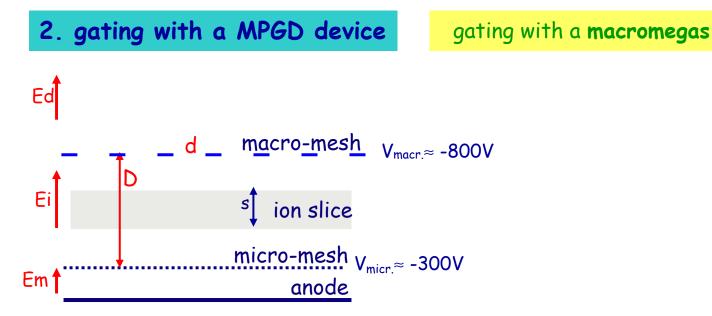




Suppression of Ion feedback in TPC

J. Va'vra,

R. Cizeron et al. NIMA419(525)1998.



new idea (may be not a good one...):

gate the ions with a "macro-mesh" with a large pitch d (200 μ m?)

in order to ensure a full electron transparency

-> probably needs also $E_i > E_d$ $E_i = 2-3 \times E_d$?

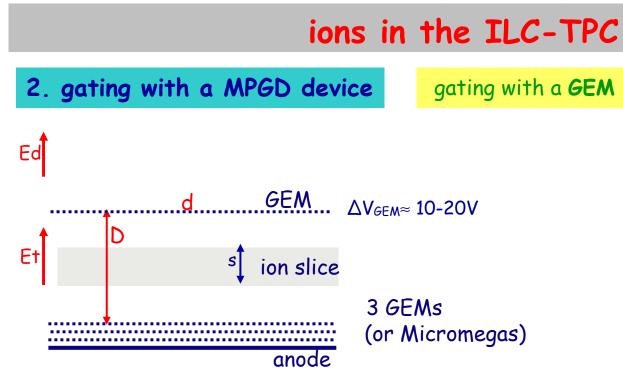
s is increased proportionally from 4mm to ~ 1cm -> D>1cm

- -> no kick on the electrons
- -> very small ExB effect

-> problems:

1. after the train (1ms) the macromesh voltage has to be increased by more than 500V within less than a few 100 μ s, in order to push back ions to the micromesh is it possible? may be not, to be studied...

2. how to hold this macromesh?



original idea by Fabio Sauli 2006:

Ion feedback suppression in time projection chambers

F. Sauli*, L. Ropelewski, P. Everaerts Nuclear Instruments and Methods in Physics Research A 560 (2006) 269

gate the ions with a GEM without multiplication (ΔV very small)

the same problem is to have a full electron transparency,

and, also, a **full transmission** from this GEM to the amplification device of course this transmission depends on the transfer field Et.

measurements by Fabio et al. AND recent simulations by a Japanese group

Ion feedback suppression in time projection chambers

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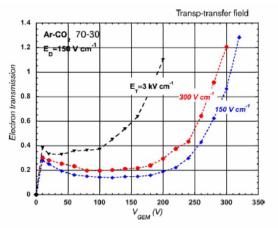


Fig. 4. Electron transmission of a standard GEM foil, measured in the pulse mode, for standard high (3 kV cm^{-1}) and low transfer fields (150 and 300 V cm⁻¹), as a function of GEM voltage. Drift field: 150 V cm^{-1} , gas filling A-CO₂ 70-30 at STP.

influence of the transfer field Et

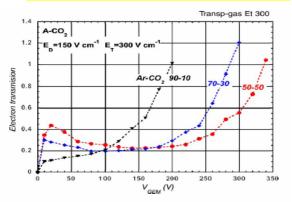


Fig. 5. Electron transmission of a standard GEM, for low transfer field $(300\,Vcm^{-1})$, as a function of GEM voltage and for three A–CO₂ mixtures: 90–10, 70–30 and 50–50.



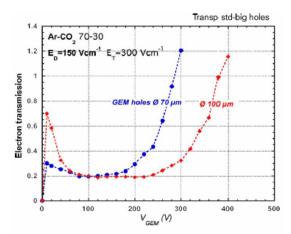
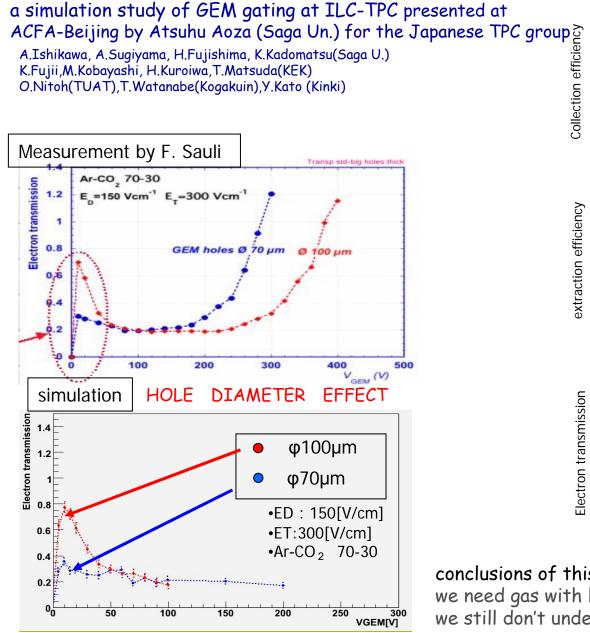
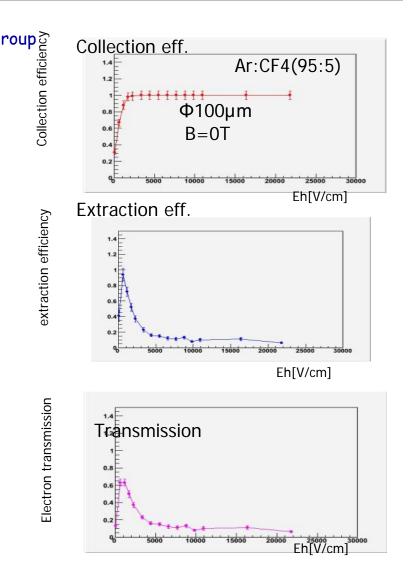


Fig. 6. Comparison of electron transmission for two GEM foils: standard (70 μ m holes at 140 μ m pitch) and large (100 μ m holes at 140 μ m pitch). Gas filling: A-CO₂ 70-30.

influence of the GEM hole size





conclusions of this presentation:

we need gas with low diffusion even at high electric field we still don't understand detail some part yet

influence of ions on the multiplication process?

an electron arriving in the multiplication region **always experiment** a slice of secondary ions, with a variable size \leq s, produced since the beginning of the train near the anode plane. so the multiplication region is never "ion free"

• Micromegas case

- due to their very high velocity (500 times higher than in the drift region) ions escape 500 times faster, but there are 500 times more ions (no gating by Micromegas) so the ion density in this gap is quite the same.
- moreover the electric field is so high in this region that probably electrons "will not see" these ions, and also the gap is very small
- -> probably no effect

• GEM case

- most of the ions originate from the last GEM hole
- due to the various regions (inside and between the GEMs) the problem is a little bit more complicate....
- will there be a problem (distortion) on the electrons? may be not ...



how to estimate ion density in the TPC from occupancy?

- difficult exercise, may be an answer from Adrian Vogel simulations very soon...
- depends also on background, gas choice (neutrons), gain, ion feedback...

fast calculation yesterday evening, assuming:

- numbers from Adrian for the hits
- gain G=5000
- ion backflow β =2x10⁻³
- ion mobility $2cm^2/(V.s)$
- v_e =8cm/ μ s
- E_{drift} = 200V/cm and R=120cm, L_{TPC} =240cm
- 10^9 voxels in the TPC

1. TPC occupancy

the max. drift time for electrons is $60\mu s$, corresponding to ~200 bunches from Adrian, there are ~4x10⁵ "hits" during this time in the TPC.

I assume that a hit will occupies after diffusion ~20 voxels

- -> 20×4×10⁵ = 8×10⁶ voxels "occupied"
- -> occupancy ~ 1%

2. ion density

- I assume very arbitrarily that 1 hit => 100 electrons released
- total number of electrons producing ions during 600ms= 3 trains (time for ions to be collected by the cathode):

 N_e =4×10⁵×100×(3300/200)×3 ~2×10⁹ ... and the same number of primary ions,

- total number of secondary ions: $N_i = NexGx\beta = 2x10^9x5x10^3x2x10^{-3} \sim 2x10^{10}$ for 3 ion slices.
- total charge per slice Q=0.7×10¹⁰×1.6×10⁻¹⁹ = 1 nC
- slice volume, with s=4mm: V~1.7×10⁴cm3
- charge density in the slice $\rho=Q/V \sim 60 \text{ fC/cm}^3$ (6fC/cm³ if G=1/ β)

is it a problem for an electron crossing this «wall» of ions????

conclusion

primary ionisation

nothing to do except to collect ions « quickly » in order to decrease its density in the TPC need to do more simulations (calculations) on the distortions induced by these ions

secondary ionisation

- probably impossible to collect secondary ions on the cathode before 200 ms
- do we need a gating device?
 - if $Ns \approx Ni$, may be not, except if the high density secondary ions slice is a problem, if Ns large, probably yes we have to gate secondary ions,
- simulations (and/ore calculations/experiments) of the **distortions** induced on electron drift (with B) are needed,
- ion mobility measurements (or calculations) are probably needed for gate optimization
- more work and thinking on gating devices:

a gate should be transparent to electrons,

should not induce distortions and ExB effects

should be optimized for a given gas mixture

... more work to be done!